



# RADIO TEST REPORT

**Test Report No.: 30DE0267-YK-01-R1**

**Applicant** : NIDEC SANKYO Corporation  
**Type of Equipment** : Contactless IC card reader  
**Model No.** : ICM0M0  
**FCC ID** : WJ6-ICM0M001A-M  
**Test regulation** : FCC Part15 Subpart C: 2009  
**Test result** : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the limits of the above regulation.
4. The test results in this test report are traceable to the national or international standards.
5. Original test report number of this report is 30DE0267-YK-01 (issued date: December 10, 2009).

**Date of test:** November 27, 28, 2008 and December 22, 2009

**Tested by:** T. Arai & G. Ishiwata  
Tatsuya Arai Go Ishiwata

T. Suzuki  
Takahiro Suzuki

**Approved by:** T. Imamura  
Toyokazu Imamura  
Manager of Yamakita EMC Lab.

**UL Japan, Inc.**

**Yamakita EMC Lab.**

907 Kawanishi, Yamakita-machi, Ashigarakami-gun, Kanagawa-ken, 258-0124 JAPAN

Telephone: +81 465 77 1011  
Facsimile: +81 465 77 2112

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**UL Japan, Inc.**

**Yamakita EMC Lab.**

907 Kawanishi, Yamakita-machi, Ashigarakami-gun, Kanagawa-ken, 258-0124 JAPAN

Telephone: +81 465 77 1011

Facsimile: +81 465 77 2112

## 1 Applicant information

Company Name : NIDEC SANKYO CORPORATION  
Address : 5329 Shimosuwa-machi, Suwa-gun, Nagano-ken, 393-8511 Japan  
Telephone Number : +81-266-27-4715  
Facsimile Number : +81-266-27-4620  
Contact Person : Junro Takeuchi

## 2 Equipment under test (E.U.T.)

### 2.1 Identification of E.U.T.

Type of Equipment : Contactless IC card reader  
Model No. : ICM0M0  
Serial No. : Refer to 4.2 of this report.  
Rating : DC24V, 10A  
Country of Mass-production : Japan  
Receipt Date of Sample : November 26, 2008  
December 2, 2009  
Condition of EUT : Production model  
Modification of EUT : No modification by the test lab.

### 2.2 Product description

Model: ICM0M0 (referred to as the EUT in this report) is Contactless IC card reader.

Equipment type : Transceiver  
Frequency of operation : 13.56MHz  
Clock frequency : 13.56MHz, 16.00MHz  
Type of modulation : ASK  
Antenna type : Loop antenna  
Antenna connector type : U. FL  
ITU code : A1D  
Operation temperature range : 0 ~ +50 deg.C.

FCC Part15.31 (e)

The RFID transmitter has a regulator which regulates the supplied voltage of DC 24V to DC 3.3V and DC5.0V. Therefore, the equipment complies power supply regulation.

FCC Part15.203 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted on the board integrally. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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**Yamakita EMC Lab.**

907 Kawanishi, Yamakita-machi, Ashigarakami-gun, Kanagawa-ken, 258-0124 JAPAN

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### 3 Test specification, procedures and results

#### 3.1 Test specification

Test specification : FCC Part 15 Subpart C: 2009, final revised on December 2, 2009  
 Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators  
 Section 15.207 Conducted limits  
 Section 15.209 Radiated emission limits, general requirements  
 Section 15.215 Additional provisions to the general radiated emission limitations.  
 Section 15.225 Operation within the bands 13.110-14.010MHz.

\*The revision on December 2, 2009 does not affect the test specification applied to the EUT.  
 The EUT complies with FCC Part 15 Subpart B. Refer to the test report 29CE0202-YK-01-B.

#### 3.2 Procedures & Results

Item	Test Procedure	Specification	Remarks	Deviation	Worst Margin	Results
Conducted emission	ANSI C63.4:2003 7. AC powerline conducted emission measurements	FCC Section15.207	-	N/A	16.5dB (21.3361MHz, QP, N)	Complied
Electric field strength of Fundamental emission	ANSI C63.4:2003 13. Measurement of intentional radiators	FCC Section15.225 (a)	Radiated	N/A	57.8dB (Vertical)	Complied
Electric field strength of Outside the allocated bands	ANSI C63.4:2003 13. Measurement of intentional radiators	FCC Section15.225 (b)(c)	Radiated	N/A	35.2dB (13.553MHz, Vertical)	Complied
Electric field strength of Spurious emission	ANSI C63.4:2003 13. Measurement of intentional radiators	FCC Section15.209 FCC Section15.225 (d)	Radiated	N/A	0.7dB (400.03MHz, Horizontal)	Complied
20dB bandwidth	ANSI C63.4:2003 13. Measurement of intentional radiators	FCC Section15.215 (c)	Radiated	N/A	-	Complied
Frequency tolerance	ANSI C63.4:2003 13. Measurement of intentional radiators	FCC Section15.225 (e)	Radiated	N/A	-	Complied

Note: UL Japan's EMI Work Procedures No.QPM05 and QPM15.

#### 3.3 Addition to standard

Item	Test Procedure	Specification	Remarks	Worst Margin	Results
Occupied bandwidth (99%)	ANSI C63.4:2003 13. Measurement of intentional radiators RSS-Gen 4.6.1	RSS-Gen 4.6.1	Conducted	-	Complied

\* Other than above, no addition, exclusion nor deviation has been made from the standard.

**UL Japan, Inc.**

**Yamakita EMC Lab.**

907 Kawanishi, Yamakita-machi, Ashigarakami-gun, Kanagawa-ken, 258-0124 JAPAN

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Facsimile: +81 465 77 2112

### 3.4 Uncertainty

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

	No.1 open site (±)	No.2 open site (±)	No.1 anechoic chamber (±)
<b>Conducted emission</b>			
150kHz-30MHz	3.5 dB	3.5 dB	3.5 dB
<b>Radiated emission (3m)</b>			
<30MHz	3.3 dB	3.2 dB	3.0 dB
30-300MHz	4.4 dB	4.5 dB	4.6 dB
300-1000MHz	4.6 dB	4.7 dB	4.7 dB

Frequency tolerance	(±)
	0.000014MHz

#### Conducted emission test

The data listed in this test report has enough margin, more than site margin.

#### Radiated emission test

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

### 3.5 Test location

UL Japan, Inc. Yamakita EMC Lab.

907, Kawanishi, Yamakita-machi, Ashigarakami-gun, Kanagawa-ken 258-0124 JAPAN

Telephone number : +81 465 77 1011

Facsimile number : +81 465 77 2112

JAB Accreditation No. : RTL02610

No. 1 test site has been fully described in a report submitted to FCC office, and accepted on July 23, 2008 (Registration No.: 95486).

IC Registration No. : 2973B-1

No. 2 test site has been fully described in a report submitted to FCC office, and accepted on February 27, 2008 (Registration No.: 466226).

IC Registration No. : 2973B-3

No. 1 anechoic chamber has been fully described in a report submitted to FCC office, and accepted on October 22, 2008 (Registration No.: 95967).

IC Registration No. : 2973B-2

Test room	Width x Depth x Height (m)	Test room	Width x Depth x Height (m)
No.1 shielded room	8.0 x 5.0 x 2.5	No.1 Semi-anechoic chamber	10.0 x 7.5 x 5.7
No.2 shielded room	5.0 x 4.0 x 2.5		
No.3 shielded room	4.0 x 5.0 x 2.7		

Open test site	Maximum measurement distance
No.1 open test site	30m
No.2 open test site	10m

### **UL Japan, Inc.**

#### **Yamakita EMC Lab.**

907 Kawanishi, Yamakita-machi, Ashigarakami-gun, Kanagawa-ken, 258-0124 JAPAN

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Facsimile: +81 465 77 2112

## 4 System test configuration

### 4.1 Justification

The EUT exercise program used during testing was designed to exercise the various system components in a manner similar to typical use.

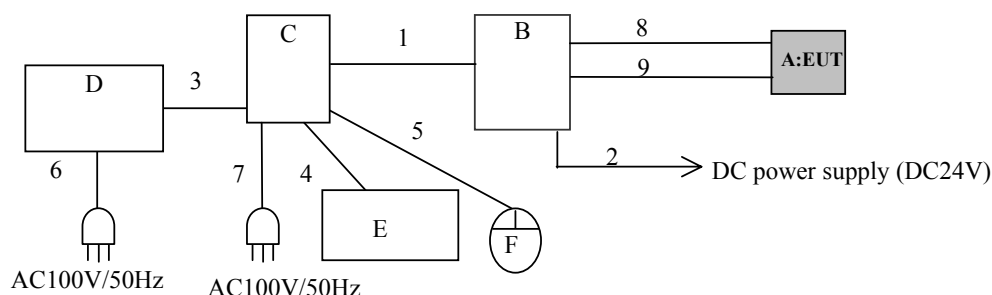
Operation: Fully – automatic operation mode

1. The card is transported from Card Hopper to communication part.
2. The card communicates.
3. The card is ejected.
4. The card is taken and it communicates.
5. The card is ejected.

\* Communication: Read/Write of 01 (16byte) data

**Justification:** The system was configured in typical fashion (as customer would normally use it) for testing.

### 4.2 Configuration and peripherals



\* Test data was taken under worse case conditions.

#### Description of EUT and support equipment

No.	Item	Model number	Serial number	Manufacturer	Remark
A	Contactless IC card reader	ICM0M0	*1)	NIDEC SANKYO	EUT
B	Contactless IC card dispenser	SCT0M0-130	R-9010008	NIDEC SANKYO	-
C	Personal computer	DHP	00146	DELL	-
D	Display	151S	BH15H4MT100520A	FUJITSU	-
E	Keyboard	FMV-KB321	761784	FUJITSU	-
F	Mouse	CA02951-6676	LZB91206992	FUJITSU	-

\*1) R-8100005 (used in November 27 and 28, 2008), R-9010008 (used on December 22, 2009)

#### List of cables used

No.	Name	Length (m)	Shield		Remark
			Cable	Connector	
1	I/F (RS232C) cable	3.0	Shielded	Unshielded	-
2	DC Power cable	1.3	Unshielded	Unshielded	-
3	RGB cable	1.7	Unshielded	Unshielded	-
4	Keyboard cable	1.5	Unshielded	Unshielded	-
5	Mouse cable	1.9	Unshielded	Unshielded	-
6	AC Power cable	2.0	Unshielded	Unshielded	-
7	AC Power cable	2.0	Unshielded	Unshielded	-
8	DC Power cable	1.0	Unshielded	Unshielded	-
9	Communication cable	1.0	Unshielded	Unshielded	-

**UL Japan, Inc.**

**Yamakita EMC Lab.**

907 Kawanishi, Yamakita-machi, Ashigarakami-gun, Kanagawa-ken, 258-0124 JAPAN

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Facsimile: +81 465 77 2112

## 5 Conducted emissions

### 5.1 Operating environment

The test was carried out in No.2 shielded room.

### 5.2 Test configuration

EUT was placed on a wooden platform of nominal size, 1m by 1.8m, raised 80cm above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT, including peripherals was aligned and was flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from LISN and excess AC cable was bundled in center. I/O cables that were connected to the peripherals were bundled in center. They were folded back and for the forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane.

Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN to the input power source. All unused 50 ohm connectors of the LISN were resistively terminated in 50 ohm when not connected to the measuring equipment.

Photographs of the set up are shown in Appendix 1.

### 5.3 Test conditions

Frequency range : 0.15 - 30MHz

### 5.4 Test procedure

The EUT was connected to a LISN (AMN). An overview sweep with peak detection has been performed. The Conducted emission measurements were made with the following detector function of the test receiver.

Detector: QP/AV

IF Bandwidth: 9kHz

### 5.5 Results

Summary of the test results : Pass

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**UL Japan, Inc.**

**Yamakita EMC Lab.**

907 Kawanishi, Yamakita-machi, Ashigarakami-gun, Kanagawa-ken, 258-0124 JAPAN

Telephone: +81 465 77 1011

Facsimile: +81 465 77 2112

## 6 Radiated emissions (Fundamental, Spurious and Outside the Allocated bands)

### 6.1 Operating environment

The test was carried out in No.1 anechoic chamber.

### 6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 0.9m by 1.8m, raised 80cm above the conducting ground plane to prevent the reflection influence. The configuration was set in accordance with ANSI C63.4: 2003. Photographs of the setup are shown in Appendix 1.

### 6.3 Test conditions

Frequency range : 9kHz - 1GHz  
 Test distance : 3m

### 6.4 Test procedure

The Radiated Electric Field Strength intensity has been measured with a ground plane and at a distance of 3m.

Frequency: From 9kHz to 30MHz at distance 3m

The EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for vertical polarization (antenna angle: 0deg to 360deg.) and horizontal polarization. Drawing of the antenna direction is shown in Figure 1.

Frequency: From 30MHz to 1GHz at distance 3m

The measuring antenna height was varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization.

Measurements were performed with QP, PK, and AV detector.

The radiated emission measurements were made with the following detector function of the test receiver.

	9kHz to 90kHz & 110kHz to 150kHz	90kHz to 110kHz	150kHz to 490kHz	490kHz to 30MHz	30MHz to 1GHz
Detector Type	PK/AV	QP	PK/AV	QP	QP
IF Bandwidth	200Hz	200Hz	10kHz	9kHz	120kHz
Measuring antenna	Loop antenna				Biconical (30-299.99MHz) Logperiodic (300MHz-1GHz)

\* FCC Part 15 Section 15.31 (f)(2) (9kHz-30MHz)

9kHz – 490kHz [Limit at 3m]= [Limit at 300m]-40log (3[m]/300[m])

490kHz – 30MHz [Limit at 3m]= [Limit at 30m]-40log (3[m]/30[m])

The EUT was tested in the direction normally used.

The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

Model	Worst position	
	Horizontal	Vertical
Antenna (9kHz - 1GHz)	Y	Y
Module (9kHz - 1GHz)	Y	X

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**Yamakita EMC Lab.**

907 Kawanishi, Yamakita-machi, Ashigarakami-gun, Kanagawa-ken, 258-0124 JAPAN

Telephone: +81 465 77 1011

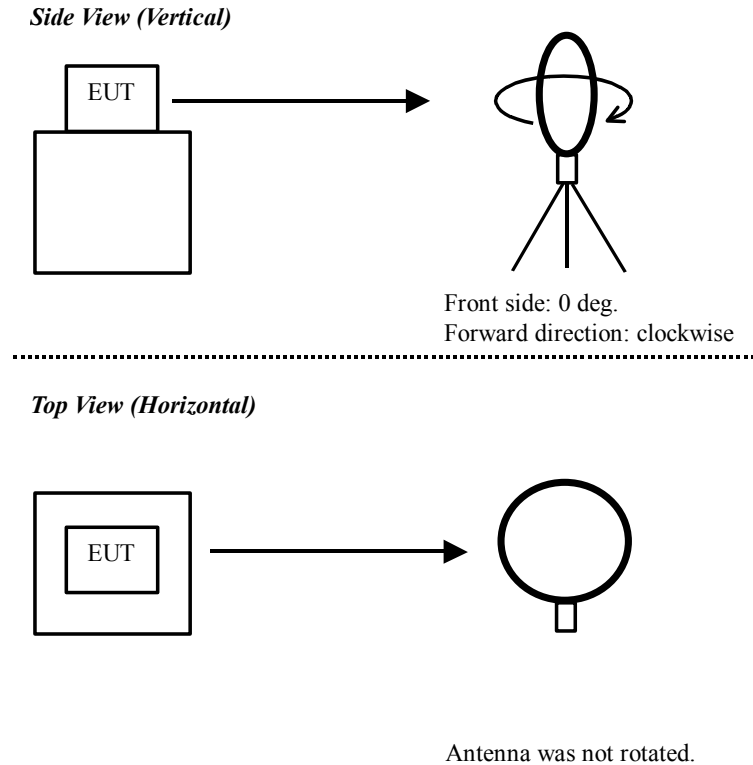
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## 6.6 Results

Summary of the test results : Pass \*No noise was detected above the 5<sup>th</sup> order harmonics.

**Figure 1: Direction of the Loop Antenna**



## 7 20dB bandwidth & Occupied bandwidth (99%)

### Test procedure

The measurement was performed in the antenna height to gain the maximum of Electric field strength.

Summary of the test results: Pass

## 8 Frequency tolerances

### Test procedure

The measurement was performed in the antenna height to gain the maximum of Electric field strength.  
The temperature test was started after the temperature stabilization time of 30 minutes.

Summary of the test results: Pass

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## UL Japan, Inc.

### Yamakita EMC Lab.

907 Kawanishi, Yamakita-machi, Ashigarakami-gun, Kanagawa-ken, 258-0124 JAPAN

Telephone: +81 465 77 1011

Facsimile: +81 465 77 2112

### **APPENDIX 1: Photographs of test setup**

Page 11	:	Conducted emission
Page 12 - 13	:	Radiated emission
Page 14 - 15	:	Pre-check of the worst position

### **APPENDIX 2: Test data**

Page 16 - 18	:	Conducted emission
Page 19 - 21	:	Radiated emission
19	:	Fundamental and Outside the Allocated bands
20 - 21	:	Spurious emission
Page 22	:	Bandwidth
Page 23 - 25	:	Frequency tolerance

### **APPENDIX 3: Test instruments**

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**UL Japan, Inc.**

**Yamakita EMC Lab.**

907 Kawanishi, Yamakita-machi, Ashigarakami-gun, Kanagawa-ken, 258-0124 JAPAN

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Facsimile: +81 465 77 2112